

SEMICONDUCTOR TM

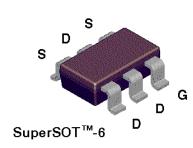
NDC631N N-Channel Logic Level Enhancement Mode Field Effect Transistor

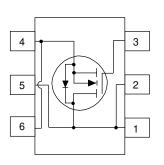
General Description

These N-Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications in notebook computers, portable phones, PCMICA cards, and other battery powered circuits where fast switching, and low in-line power loss are needed in a very small outline surface mount package.

Features

- 4.1 A, 20 V. $R_{DS(ON)} = 0.06 \Omega @ V_{GS} = 4.5 V$ $R_{DS(ON)} = 0.075 \Omega @ V_{GS} = 2.7 V.$
- Proprietary SuperSOT[™]-6 package design using copper lead frame for superior thermal and electrical capabilities.
- High density cell design for extremely low R_{DS(ON)}.
- Exceptional on-resistance and maximum DC current capability.





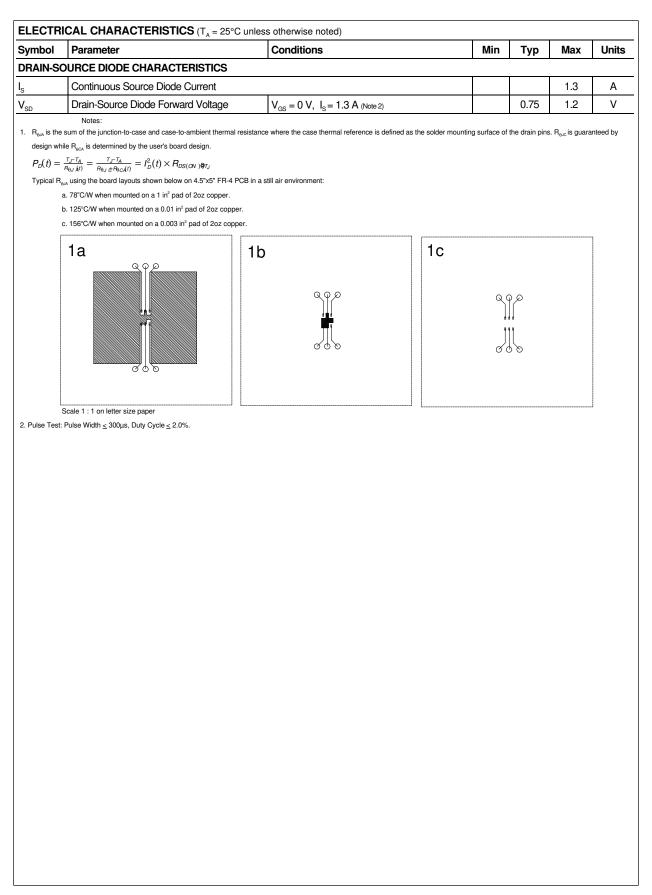
Absolute Maximum Ratings $T_{A} = 25^{\circ}C$ unless otherwise note

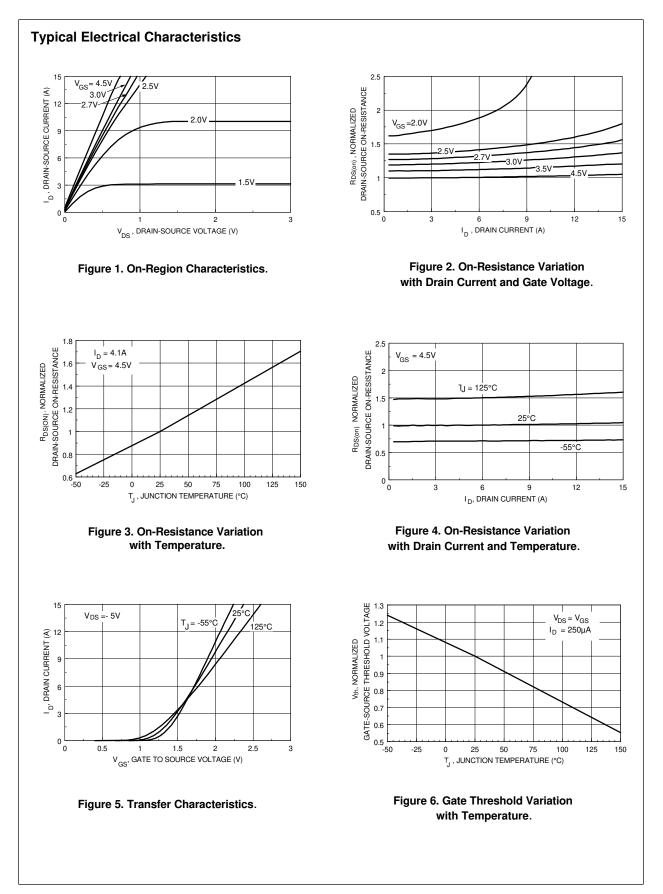
Symbol	Parameter		NDC631N	Units
V _{DSS}	Drain-Source Voltage Gate-Source Voltage - Continuous		20	V
V_{GSS}			8	V
l _D	Drain Current - Continuous	(Note 1a)	4.1	А
	- Pulsed		15	
P _D	Maximum Power Dissipation	(Note 1a)	1.6	W
		(Note 1b)	1	
		(Note 1c)	0.8	
T_,T _{stg}	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS			
R _{øja}	Thermal Resistance, Junction-to-Ar	nbient (Note 1a)	78	°C/W
R _{θJC}	Thermal Resistance, Junction-to-Ca	ASE (Note 1)	30	°C/W

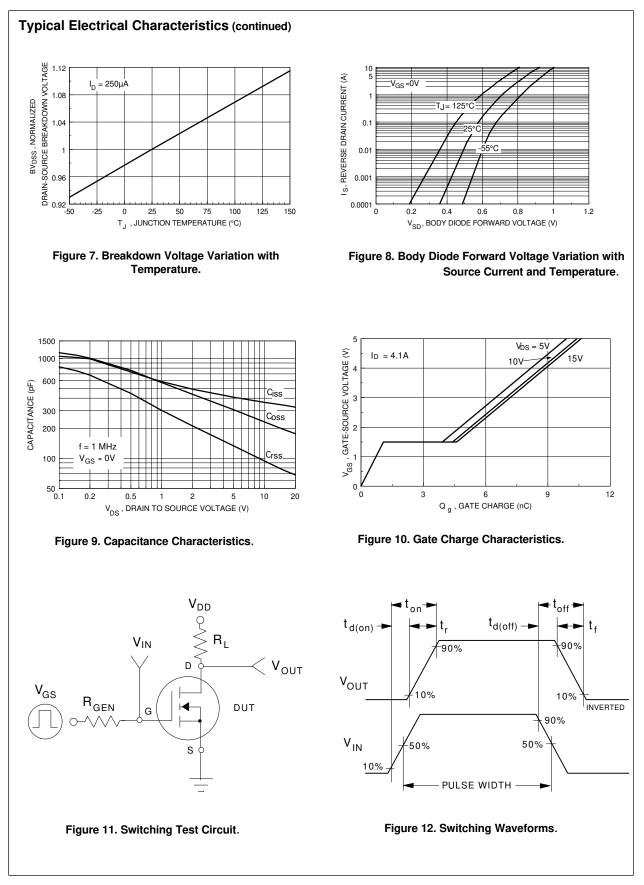
©1997 Fairchild Semiconductor Corporation

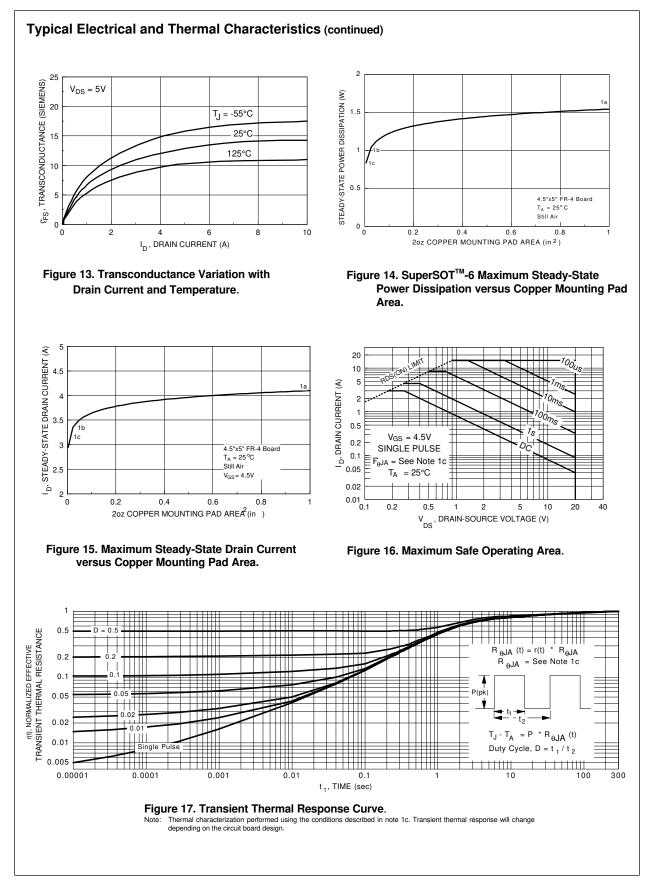
July 1996

Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		20			V
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 16 V, V_{GS} = 0 V$				1	μA
			T _J = 55°C			10	μA
	Gate - Body Leakage, Forward	$V_{GS} = 8 V, V_{DS} = 0 V$				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -8 V, V_{DS} = 0 V$				-100	nA
ON CHA	RACTERISTICS (Note 2)				-		
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{_{DS}} = V_{_{GS}}, \ I_{_{D}} = 250 \ \mu A$		0.4	0.7	1	V
			T _J = 125°C	0.3	0.5	0.8	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 4.1 \text{ A}$			0.039	0.06	Ω
- (-)			T _J = 125°C		0.06	0.11	
		$V_{GS} = 2.7 \text{ V}, \ I_{D} = 3.6 \text{ A}$			0.05	0.075	
I _{D(on)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$		15			А
9 _{FS}	Forward Transconductance	$V_{DS} = 4.5 \text{ V}, \text{ I}_{D} = 4.1 \text{ A}$			12		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			365		pF
C _{oss}	Output Capacitance				230		pF
C _{rss}	Reverse Transfer Capacitance				95		pF
SWITCHI	NG CHARACTERISTICS (Note 2)				-		
t _{D(on)}	Turn - On Delay Time	$V_{DD} = 5 V, I_{D} = 1 A,$			9	17	ns
ţ,	Turn - On Rise Time	$V_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_{\text{GEN}} = 6 \Omega$			25	45	ns
t _{D(off)}	Turn - Off Delay Time				28	50	ns
t,	Turn - Off Fall Time				8	15	ns
Q _g	Total Gate Charge	$V_{\rm DS} = 10 \rm V,$			10	14	nC
Q _{gs}	Gate-Source Charge	$I_{\rm D} = 4.1 \text{A}, V_{\rm GS} = 4.5 \text{V}$			1		nC
Q_{gd}	Gate-Drain Charge				3.3		nC

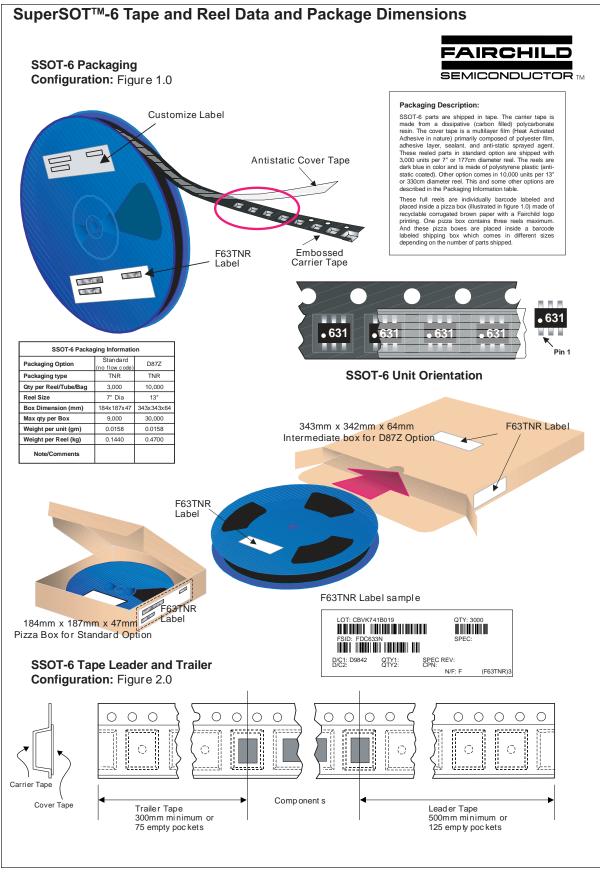




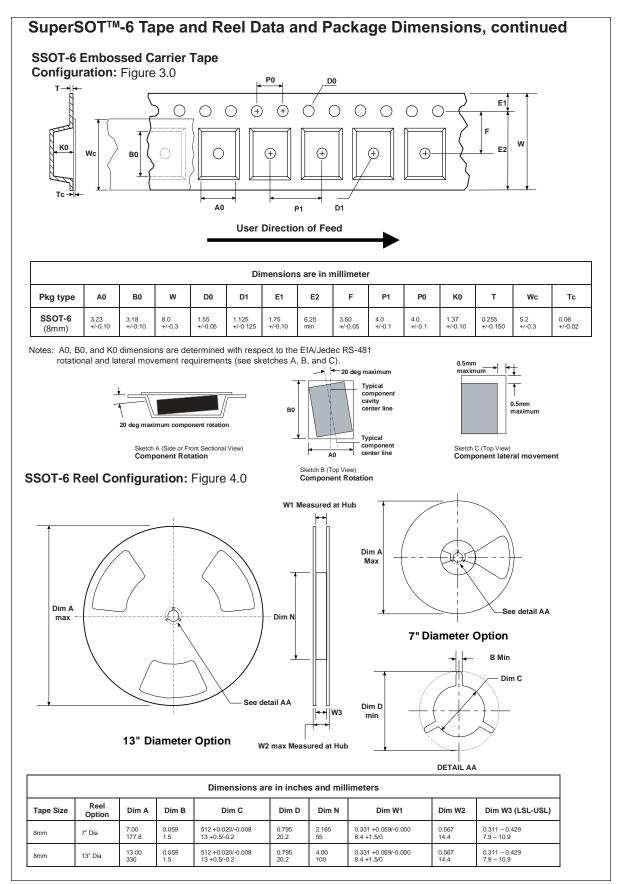




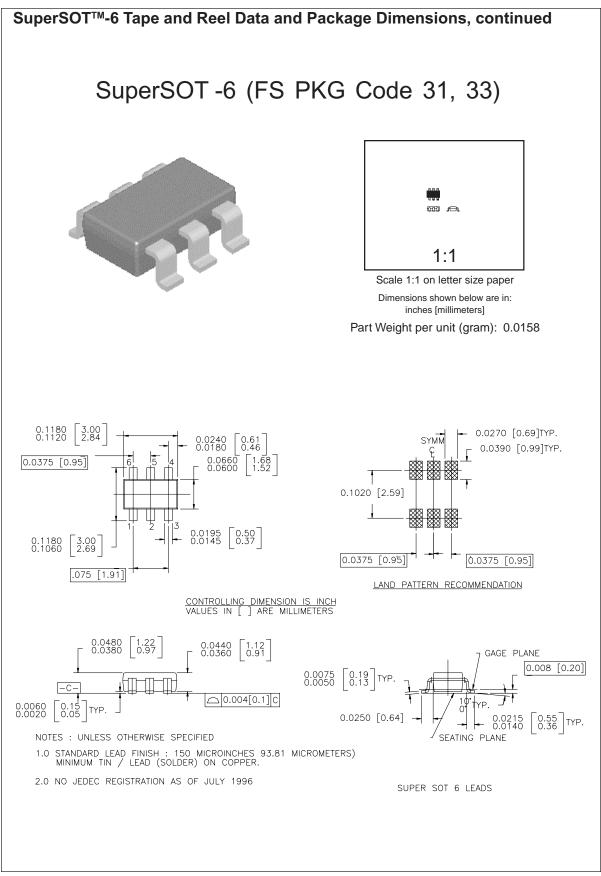
NDC631N Rev.D1



August 1999, Rev. C



July 1999, Rev. C



September 1998, Rev. A

TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACExTM CoolFETTM CROSSVOLTTM E²CMOSTM FACTTM FACT Quiet SeriesTM FAST[®] FAST[®] FASTrTM GTOTM HiSeCTM ISOPLANAR™ MICROWIRE™ POP™ PowerTrench® QFET™ QS™ Quiet Series™ SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SyncFET™ TinyLogic™ UHC™ VCX™

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user. 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.